

700V Super-junction Power MOSFET

Description

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Super-junction power MOSFET is a revolutionary technology for high voltage power MOSFETs, designed according to the SJ principle. The Multi-EPI SJ MOSFET provide an extremely low switching, communication and conduction losses device with highest robustness make especially resonant switching applications more reliable, more efficient, lighter and cooler, designed by Wuxi Unigroup Microelectronics Company.

Features	A	Applications			
• Very low FOM RDS(on)×0					
• 100% avalanche tested	•	Uninterruptible P	ower Supply (UPS)		
• Easy to use/drive	•	Power Factor Correction (PFC)			
RoHS compliant					
DP DP DF	N 5*6	Gate	ain RoHS urce		
Device Marking and I	Package Information				
Device	Package		Marking		
TPG70R600M	DFN 5*6		70R600M		
Key Performance Pa	arameters				
····, · ···					
Parameter	Value		Unit		
			Unit V		
Parameter V _{DS} @ T _{j,max}	Value				
Parameter V _{DS} @ T _{j,max}	Value 750		V		
Parameter V _{DS} @ T _{j,max} R _{DS(on),max}	Value 750 0.6		ν Ω		
Parameter V _{DS} @ T _{j,max} R _{DS(on),max} Q _{g,typ} I _D	Value 750 0.6 13		V Ω nC		
Parameter V _{DS} @ T _{j,max} R _{DS(on),max} Q _{g,typ}	Value 750 0.6 13 7		V Ω nC A		



Absolute Maximum Ra	atings T _c = 25°C, unles	ss othe	erwise noted			
Parameter			Symbol	Value	Unit	
	T _C = 25°C			7	<u> </u>	
Continuous Drain Current	T _C = 100°C		Ι _D	4.2	— A	
Pulsed Drain Current (note		note1)	I _{D,pulse}	21	А	
Gate-Source Voltage			V _{GSS}	±30	V	
Single Pulse Avalanche Energy		note2)	E _{AS}	142	mJ	
Repetitive Avalanche Energy	(n	note2)	E _{AR}	0.21	mJ	
Avalanche Current			I _{AR}	1.3	Α	
MOSFET dv/dt Ruggedness, V _{DS} = 0480V			dv/dt	50	V/ns	
Power Dissipation For DFN 5*6			P _D	63	w	
Continuous Diode Forward Current			I _S	6	— A	
Diode Pulsed Current		note1)	I _{S,pulse}	21		
Reverse Diode dv/dt		note3)	dv/dt	15	V/ns	
Maximum Diode Commutation Speed		note3)	di _f /dt	500	A/µs	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	-55~+150	°C	

Thermal Resistance For DFN5*6					
Parameter	Symbol	Value	Unit		
Thermal Resistance, Junction-to-Case	R _{thJC}	2.0	°C/W		
Thermal Resistance, Junction-to-Ambient	R _{thJA}	62	-0/00		



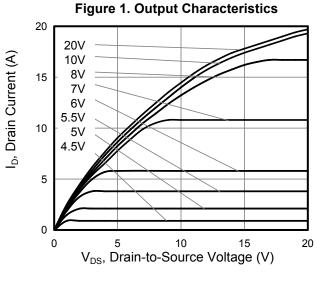
Description			Value				
Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit	
Static Characteristics	•	· · · · · ·					
Drain-Source Breakdown Voltage	V _{(BR)DSS}	$V_{GS} = 0V, I_{D} = 250 \mu A$	700			V	
Zaro Cata Valtago Drain Current		V_{DS} = 700V, V_{GS} = 0V, T_{J} = 25°C			1	μA	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 700V, V _{GS} = 0V, T _J = 150°C			100		
Gate-Source Leakage Current	I _{GSS}	$V_{GS} = \pm 30V$			±100	nA	
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_D = 250 \mu A$	2.5		4.5	V	
Drain-Source On-State-Resistance	R _{DS(on)}	V _{GS} = 10V, I _D = 3.5A		0.53	0.6	Ω	
Gate Resistance	R _G	f = 1.0MHz open drain		7		Ω	
Dynamic Characteristics					•		
Input Capacitance	C _{iss}			509		pF	
Output Capacitance	C _{oss}	$V_{GS} = 0V,$ $V_{DS} = 100V,$		23			
Reverse Transfer Capacitance	C _{rss}	f = 1.0MHz		1.5			
Total Gate Charge	Qg			13		nC	
Gate-Source Charge	Q _{gs}	V _{DD} = 520V, I _D = 7A, V _{GS} = 10V		2.8			
Gate-Drain Charge	Q _{gd}			5.6			
Turn-on Delay Time	t _{d(on)}			55			
Turn-on Rise Time	t _r	V _{DD} = 400V, I _D = 7A,		61			
Turn-off Delay Time	$t_{d(off)}$	$R_{G} = 25\Omega$		117		ns	
Turn-off Fall Time	t _f			42			
Drain-Source Body Diode Characte	ristics						
Body Diode Forward Voltage	V_{SD}	$T_J = 25^{\circ}C$, $I_{SD} = 3.5A$, $V_{GS} = 0V$		0.9	1.2	V	
Reverse Recovery Time	t _{rr}			321		ns	
Reverse Recovery Charge	Q _{rr}	V _R = 400V, I _F = 7A, di _F /dt = 100A/µs		3.4		μC	
Peak Reverse Recovery Current	I _{rrm}	1		21.2		А	

Notes

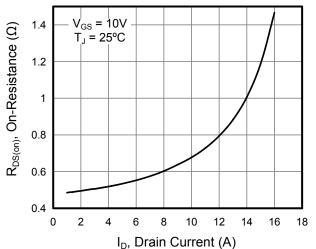
- 1. Repetitive Rating: Pulse width limited by maximum junction temperature
- 2. I_{AS} = 2.4A, V_{DD} = 50V, R_G = 25 Ω , Starting T_J = 25°C
- 3. Identical low side and high side switch with identical ${\sf R}_{\sf G}$



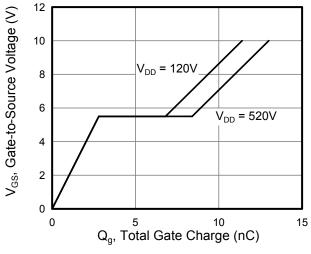
Typical Characteristics $T_J = 25^{\circ}C$, unless otherwise noted

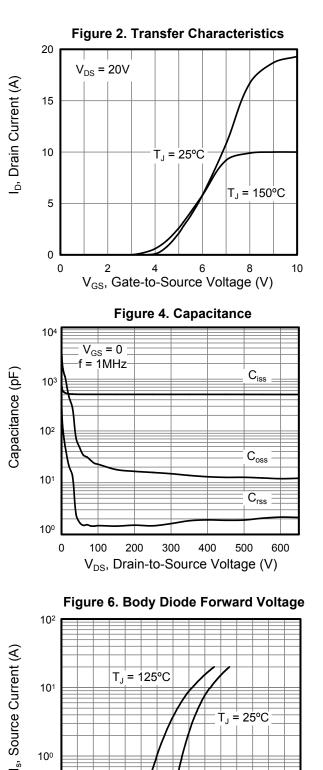












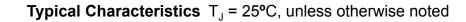
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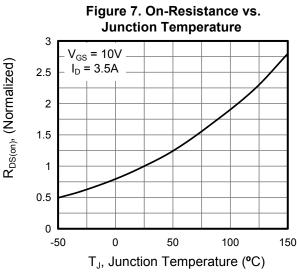
 V_{SD} , Source-to-Drain Voltage (V)

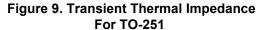
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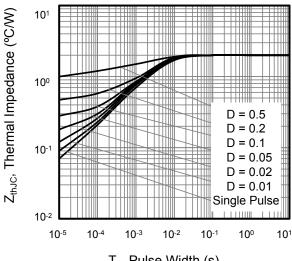
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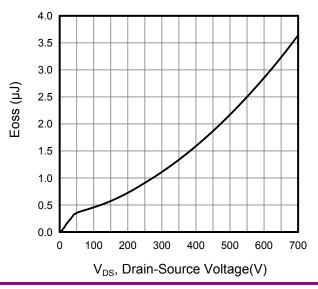


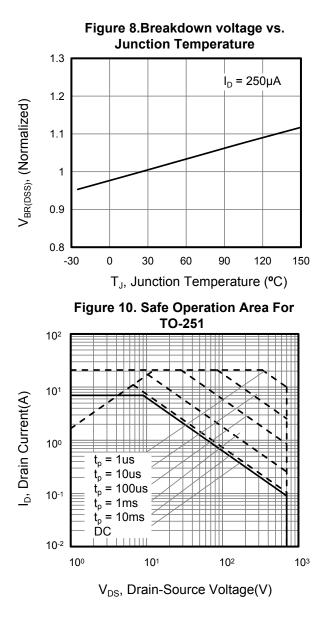




T_p, Pulse Width (s)

Figure 11. Typ. Coss Stored Energy







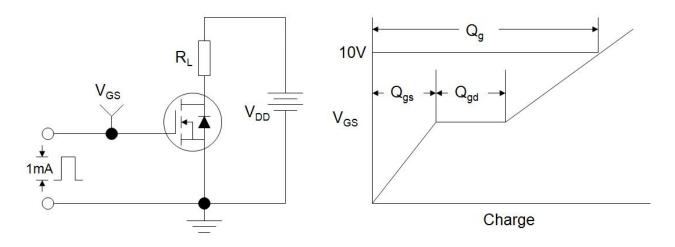


Figure B: Resistive Switching Test Circuit and Waveform

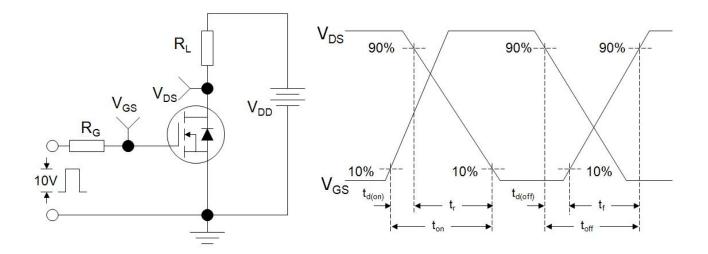
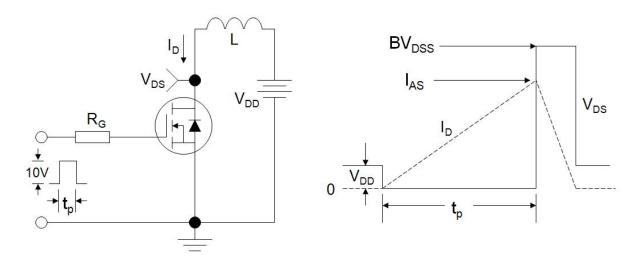
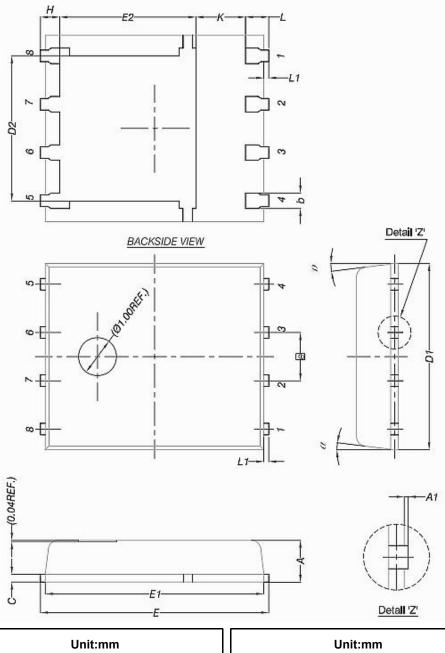


Figure C: Unclamped Inductive Switching Test Circuit and Waveform







	Unit:mm				Unit	:mm	
Symbol	Min.	Nom	Max.	Symbol	Min.	Nom	Max.
А	0.90	1.00	1.10	E2	3.38	3.58	3.78
A1	0	-	0.05	е	1.27 BSC		
b	0.33	0.41	0.51	н	0.41	0.51	0.61
С	0.20	0.25	0.30	к	1.10	-	-
D1	4.80	4.90	5.00	L	0.51	0.61	0.71
D2	3.61	3.81	3.96	L1	0.06	0.13	0.20
E	5.90	6.00	6.10	α	0°	-	12°
E1	5.70	5.75	5.80				



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